

Search Notes

Application/Control No.

10/815,106

Examiner

Shin-Hon Chen

Applicant(s)/Patent under
Reexamination

ICHIKAWA ET AL.

Art Unit

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SEARCHED

Class	Subclass	Date	Examiner
713	158,168	6/8/2007	S.C.
713	169,170	6/8/2007	S.C.
713	156	6/8/2007	S.C.

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPAT, PGPUB, DERWENT, JPO, EPO (BRS search- see search history)	6/8/2007	S.C.